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PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10044956	01/15/2002	073		2856	A. J. L.

\*\*APPLICANTS: Nakayama Keiji; Hatsukano Kanichi;

\*\*CONTINUING DATA VERIFIED:

\*\* FOREIGN APPLICATIONS VERIFIED:

JAPAN 2001-6822 01/15/2001

PG-PUB  DO NOT PUBLISH

RESCIND

ATTORNEY DOCKET NO

Foreign priority claimed

35 USC 119 conditions met

Verified and Acknowledged Examiner's initials

**BEST AVAILABLE COPY**

TITLE : Method of and apparatus for measuring and evaluating material strength by detecting charged particles

U.S. DEPT. OF COMM./PAT. & TM-PTO-436L(Rev. 12-94)

NOTICE OF ALLOWANCE MAILED

Assistant Examiner

CLAIMS ALLOWED

Total Claims  Print Claim for O.G.

ISSUE FEE

Amount Due  Date Paid

DRAWING

Sheet Draw.  Fig. Draw.  Print Fig.

TERMINAL

DISCLAIMER

Primary Examiner

Application Examiner

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